

Search Notes



Application/Control No.

09/767,730

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under
Reexamination

BUCKLEY ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	10/05	DN
5			
6			
7			
8			
9			
10			
26			
706	45	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES
(INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US patent PGPub	10/05	DN
II Foreign EPO SPO Derwent	↓	↓
III NPL Dialog	↓	↓
Review parent RCE	10/05	DN